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Applied Physics Letters (ISSN: 0003-6951) is published weekly by the American Institute of Physics, Suite 1N01, 2 Huntington Quadrangle, Melville, NY 11747-4502. The 2012 print+online base price is US\$4,130. POSTMASTER: Send address changes to *Applied Physics Letters*, AIP, Suite 1N01, 2 Huntington Quadrangle, Melville, NY 11747-4502. Periodicals postage rates are paid at Huntington Station, NY 11746, and additional mailing offices.